

FCC Test Report

Report No. : 1812C60268512502

Applicant : Shenzhen Seenda Technology Co., Ltd.

Address : #3402-3405,3410-3411,Building B,Longhua
District Digital Innovation Center,Beizhan
Community,Minzhi Street,Longhua
District,Shenzhen,China

Product Name : Wireless Keyboard

Report Date : 2026-06-05



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TEST REPORT

Applicant : Shenzhen Seenda Technology Co., Ltd.
Manufacturer : Shenzhen Seenda Technology Co., Ltd.
Product Name : Wireless Keyboard
Model No. : CE64-3 Pro
Trade Mark : Seenda
Rating(s) : Input: 5V=700mA
Battery Capacity: DC 3.7V, 1800mAh
47 CFR Part 15.247
Test Standard(s) : **KDB 558074 D01 15.247 Meas Guidance v05r02**
ANSI C63.10-2020+Cor.1-2023

The device described above is tested by Shenzhen Anbotek Compliance Laboratory Limited to determine the maximum emission levels emanating from the device and the severe levels of the device can endure and its performance criterion. The measurement results are contained in this test report and Shenzhen Anbotek Compliance Laboratory Limited is assumed full of responsibility for the accuracy and completeness of these measurements. Also, this report shows that the EUT (Equipment Under Test) is technically compliant with above listed standard(s) requirements. This report applies to above tested sample only and shall not be reproduced in part without written approval of Shenzhen Anbotek Compliance Laboratory Limited.

Date of Receipt: 2026-05-14

Date of Test: 2026-05-14 to 2026-06-05

Prepared By:

Cecilia Chen

(Cecilia Chen)

Approved & Authorized Signer:

Hugo Chen

(Hugo Chen)

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Revision History

Report Version	Description	Issued Date
R00	Original Issue.	2026-06-05

1. General Information

1.1. Client Information

Applicant	:	Shenzhen Seenda Technology Co., Ltd.
Address	:	#3402-3405,3410-3411,Building B,Longhua District Digital Innovation Center,Beizhan Community,Minzhi Street,Longhua District,Shenzhen,China
Manufacturer	:	Shenzhen Seenda Technology Co., Ltd.
Address	:	#3402-3405,3410-3411,Building B,Longhua District Digital Innovation Center,Beizhan Community,Minzhi Street,Longhua District,Shenzhen,China
Factory	:	Shenzhen Hangshi Electronic Technology Co., LTD
Address	:	Floor 2, Building A1, Zone G, Democratic West Industrial Zone, Democratic Community, Shajing Street, Bao 'an District, Shenzhen, China

1.2. Description of Device (EUT)

Product Name	:	Wireless Keyboard
Model No.	:	CE64-3 Pro
Trade Mark	:	Seenda
Test Power Supply	:	DC 5V from adapter input AC 120V/60Hz; DC 3.7V Battery inside
Test Sample No.	:	1-2-1(Normal Sample), 1-2-2(Engineering Sample)
Adapter	:	N/A
RF Specification		
Operation Frequency	:	2403MHz to 2480MHz
Number of Channel	:	16
Modulation Type	:	GFSK
Antenna Type	:	PCB Antenna
Antenna Gain(Peak)	:	2.34dBi
Remark: (1) All of the RF specification are provided by customer. (2) For a more detailed features description, please refer to the manufacturer's specifications or the User's Manual.		

1.3. Auxiliary Equipment Used During Test

Title	Manufacturer	Model No.	Serial No.
Xiaomi 33W adapter	Xiaomi	MDY-11-EX	SA62212LA04358J

1.4. Operation channel list

Operation Band:

Channel	Frequency (MHz)	Channel	Frequency (MHz)	Channel	Frequency (MHz)	Channel	Frequency (MHz)
1	2403	5	2407	9	2414	13	2419
2	2426	6	2422	10	2436	14	2439
3	2441	7	2445	11	2459	15	2453
4	2463	8	2466	12	2473	16	2480

1.5. Description of Test Modes

Pretest Modes	Descriptions
TM1	Keep the EUT in continuously transmitting mode (non-hopping).
TM2	Keep the EUT in continuously transmitting mode (hopping).

1.6. Measurement Uncertainty

Parameter	Uncertainty
Conducted emissions (AMN 150kHz~30MHz)	3.0dB
Occupied Bandwidth	552Hz
Conducted Output Power	0.84dB
Dwell Time	2%
Conducted Spurious Emission	1.24dB
Radiated spurious emissions (above 1GHz)	1G-6GHz: 4.64dB; 6G-18GHz: 4.82dB 18G-40GHz: 5.62dB
Radiated emissions (Below 30MHz)	3.14dB
Radiated spurious emissions (30MHz~1GHz)	Horizontal: 4.44dB; Vertical: 4.82dB
The measurement uncertainty and decision risk evaluated according to AB/WI-RF-F-032. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.	

1.7. Additional Instructions

Power level setup in software: BK32xxRF Test V2.1.7

Operation Band:

Mode	Channel(MHz)	Power level	Transmitting type
2.4G	2403	default	data pack TX
2.4G	2441	default	data pack TX
2.4G	2480	default	data pack TX

1.8. Test Summary

Test Items	Test Modes	Status
Antenna requirement	/	P
Conducted Emission at AC power line	Mode1	P
20dB Bandwidth	Mode1	P
Maximum Conducted Output Power	Mode1	P
Channel Separation	Mode2	P
Number of Hopping Frequencies	Mode2	P
Dwell Time	Mode2	P
Emissions in non-restricted frequency bands	Mode1,2	P
Band edge emissions (Radiated)	Mode1	P
Emissions in restricted frequency bands (below 1GHz)	Mode1	P
Emissions in restricted frequency bands (above 1GHz)	Mode1	P
Note: P: Pass N: N/A, not applicable		

1.9. Description of Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

FCC-Registration No.:279531

Shenzhen Anbotek Compliance Laboratory Limited, EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration No. 279531.

Test Location

Shenzhen Anbotek Compliance Laboratory Limited.
Sogood Industrial Zone Laboratory & 1/F. of Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Subdistrict, Bao'an District, Shenzhen, Guangdong, China.

1.10. Disclaimer

1. The test report is invalid if not marked with the signatures of the persons responsible for preparing and approving the test report.
2. The test report is invalid if there is any evidence and/or falsification.
3. The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein.
4. This document may not be altered or revised in any way unless done so by Anbotek and all revisions are duly noted in the revisions section.
5. Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.
6. The authenticity of the information provided by the customer is the responsibility of the customer and the laboratory is not responsible for its authenticity.
7. The data in this report will be synchronized with the corresponding national market supervision and management departments and cross-border e-commerce platforms as required by regulatory agencies.

The laboratory is only responsible for the data released by the laboratory, except for the part provided by the applicant.

1.11. Test Equipment List

Conducted Emission at AC power line					
Item	Equipment	Manufacturer	Model No.	Last Cal.	Cal.Due Date
1	L.I.S.N. Artificial Mains Network	Rohde & Schwarz	ENV216	2025-09-05	2026-09-04
2	Three Phase V-type Artificial Power Network	CYBERTEK	EM5040DT	2025-12-30	2026-12-29
3	EMI Test Receiver(CE1#)	Rohde & Schwarz	ESCI	2025-12-30	2026-12-29
4	Artificial Mains Network	Schwarzbeck	PVDC 8301	2025-12-30	2026-12-29
5	Software Name EZ-EMC	Farad Technology	ANB-03A	/	/
6	Pulse limiter	EMtrace	PL00903-1#	2025-12-30	2026-12-29

20dB Bandwidth
Maximum Conducted Output Power
Channel Separation
Number of Hopping Frequencies
Dwell Time
Emissions in non-restricted frequency bands

Item	Equipment	Manufacturer	Model No.	Last Cal.	Cal.Due Date
1	Constant Temperature Humidity Chamber	ZHONGJIAN	ZJ-HWHS80B	2025-08-29	2026-08-28
2	DC Power Supply	IVYTECH	IV3605	2025-09-05	2026-09-04
3	Spectrum Analyzer	Rohde & Schwarz	FSV40-N	2025-12-29	2026-12-28
4	MXA Spectrum Analysis	KEYSIGHT	N9020A	2025-12-29	2026-12-28
5	Oscilloscope	Tektronix	MDO3012	2025-09-30	2026-09-29
6	MXG RF Vector Signal Generator	Agilent	N5182A	2025-12-29	2026-12-28
7	RF Test software	Toscend	JS1120-3	/	/

Band edge emissions (Radiated) Emissions in frequency bands (above 1GHz)					
Item	Equipment	Manufacturer	Model No.	Last Cal.	Cal.Due Date
1	EMI Test Receiver(RE2/3#)	Rohde & Schwarz	ESR26	2025-12-30	2026-12-29
2	EMI Preamplifier	SKET Electronic	LNPA-0118G-45	2025-12-30	2026-12-29
3	Double Ridged Horn Antenna	SCHWARZBECK	BBHA 9120D	2025-10-27	2028-10-26
4	EMI Test Software EZ-EMC	SHURPLE	N/A	/	/
5	Horn Antenna	A-INFO	LB-180400-KF	2024-01-22	2027-01-21
6	Spectrum Analyzer	Rohde & Schwarz	FSV40-N	2025-12-29	2026-12-28
7	Amplifier	Talent Microwave	TLLA18G40G-53-30	2026-01-05	2027-01-04

Emissions in frequency bands (below 1GHz)					
Item	Equipment	Manufacturer	Model No.	Last Cal.	Cal.Due Date
1	EMI Test Receiver(RE2/3#)	Rohde & Schwarz	ESR26	2025-12-30	2026-12-29
2	Pre-amplifier	SONOMA	310N	2025-12-30	2026-12-29
3	Bilog Broadband Antenna	Schwarzbeck	VULB9163	2025-10-26	2028-10-25
4	EMI Preamplifier	SKET Electronic	LNPA-0118G-45	2025-12-30	2026-12-29
5	Double Ridged Horn Antenna	SCHWARZBECK	BBHA 9120D	2025-10-27	2028-10-26
6	Loop Antenna (9K-30M)	Schwarzbeck	FMZB1519B	2025-09-05	2026-09-04
7	EMI Test Software EZ-EMC	SHURPLE	N/A	/	/
8	MXA Spectrum Analysis	Agilent	N9020A	2025-09-05	2026-09-04
9	MXG RF Vector Signal Generator	Agilent	N5182A	2025-12-29	2026-12-28
10	DC Power Supply	LW	TPR-6420D	2025-10-10	2026-10-09
11	Constant Temperature Humidity Chamber	ZHONGJIAN	ZJ-KHWS80B	2025-10-10	2026-10-09
12	Wideband Radio Communication Tester	Rohde & Schwarz	CMW 500	2025-12-29	2026-12-28
13	High-Pass Filter	CDKMV	ZHPF-BM1100-4730	2025-10-10	2026-10-09
14	High-Pass Filter	CDKMV	ZHPF-M3.5-18G-3834	2025-12-30	2026-12-29

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2. Antenna requirement

Test Requirement:	Refer to 47 CFR Part 15.203, an intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator shall be considered sufficient to comply with the provisions of this section.
Test Method:	---

2.1. Conclusion

The antenna is a PCB Antenna which permanently attached, and the best case gain of the antenna is 2.34dBi. It complies with the standard requirement.

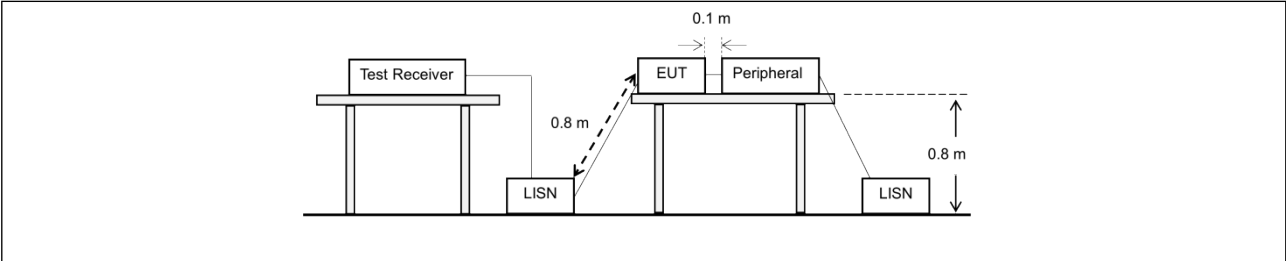
3. Conducted Emission at AC power line

Test Requirement:	Refer to 47 CFR 15.207(a), Except as shown in paragraphs (b)and (c)of this section, for an intentional radiator that is designed to be connected to the public utility (AC) power line, the radio frequency voltage that is conducted back onto the AC power line on any frequency or frequencies, within the band 150 kHz to 30 MHz, shall not exceed the limits in the following table, as measured using a 50 μ H/50 ohms line impedance stabilization network (LISN).		
Test Limit:	Frequency of emission (MHz)	Conducted limit (dB μ V)	
		Quasi-peak	Average
	0.15-0.5	66 to 56*	56 to 46*
	0.5-5	56	46
	5-30	60	50
	*Decreases with the logarithm of the frequency.		
Test Method:	ANSI C63.10-2020+Cor.1-2023 section 6.2		
Procedure:	Refer to ANSI C63.10-2020+Cor.1-2023 section 6.2, standard test method for ac power-line conducted emissions from unlicensed wireless devices		

3.1. EUT Operation

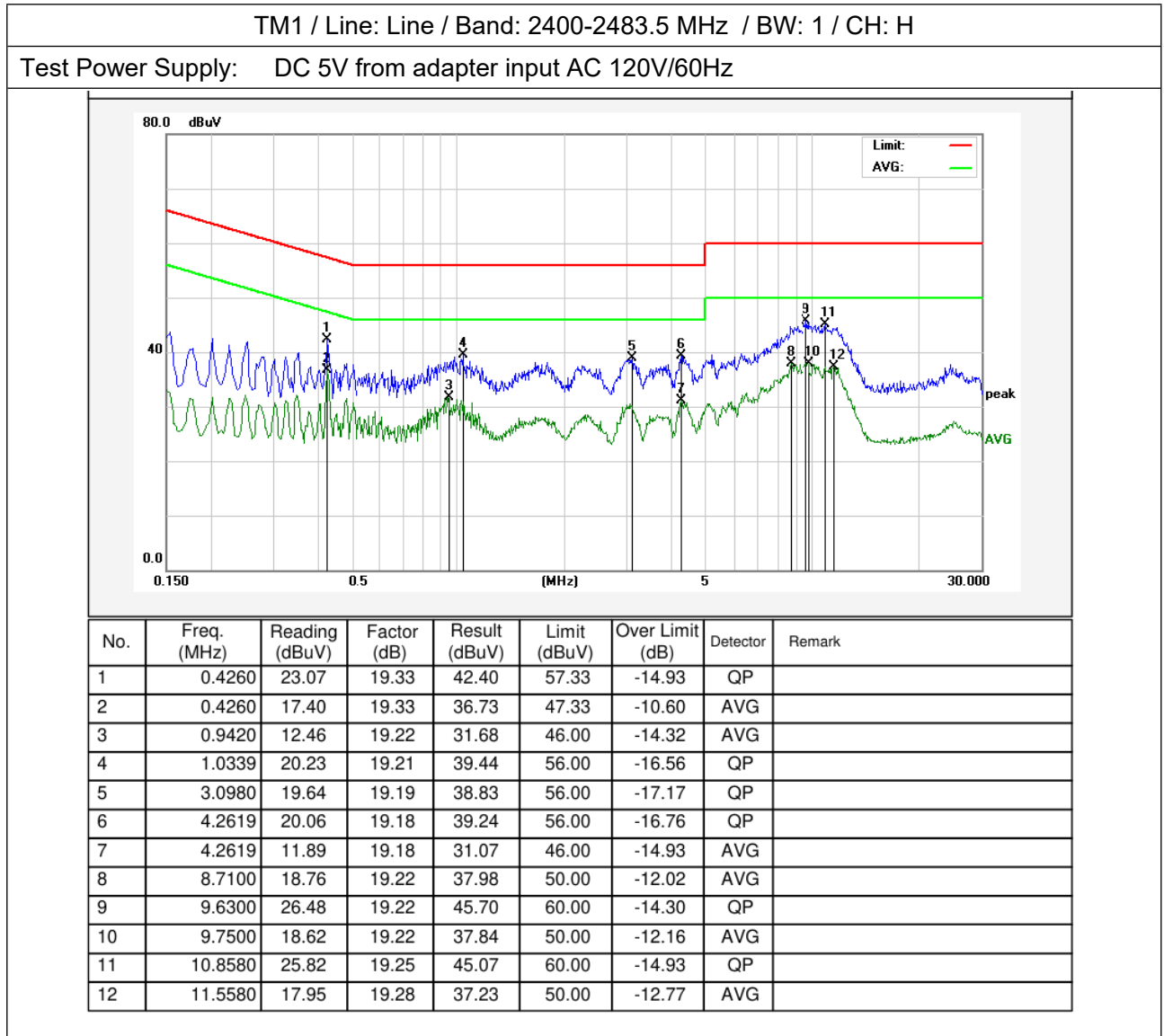
Operating Environment:	
Test mode:	1: TX (Non-Hopping): Keep the EUT in continuously transmitting mode (non-hopping).

3.2. Test Setup



3.3. Test Data

Temperature:	24.5 °C	Humidity:	62 %	Atmospheric Pressure:	101 kPa
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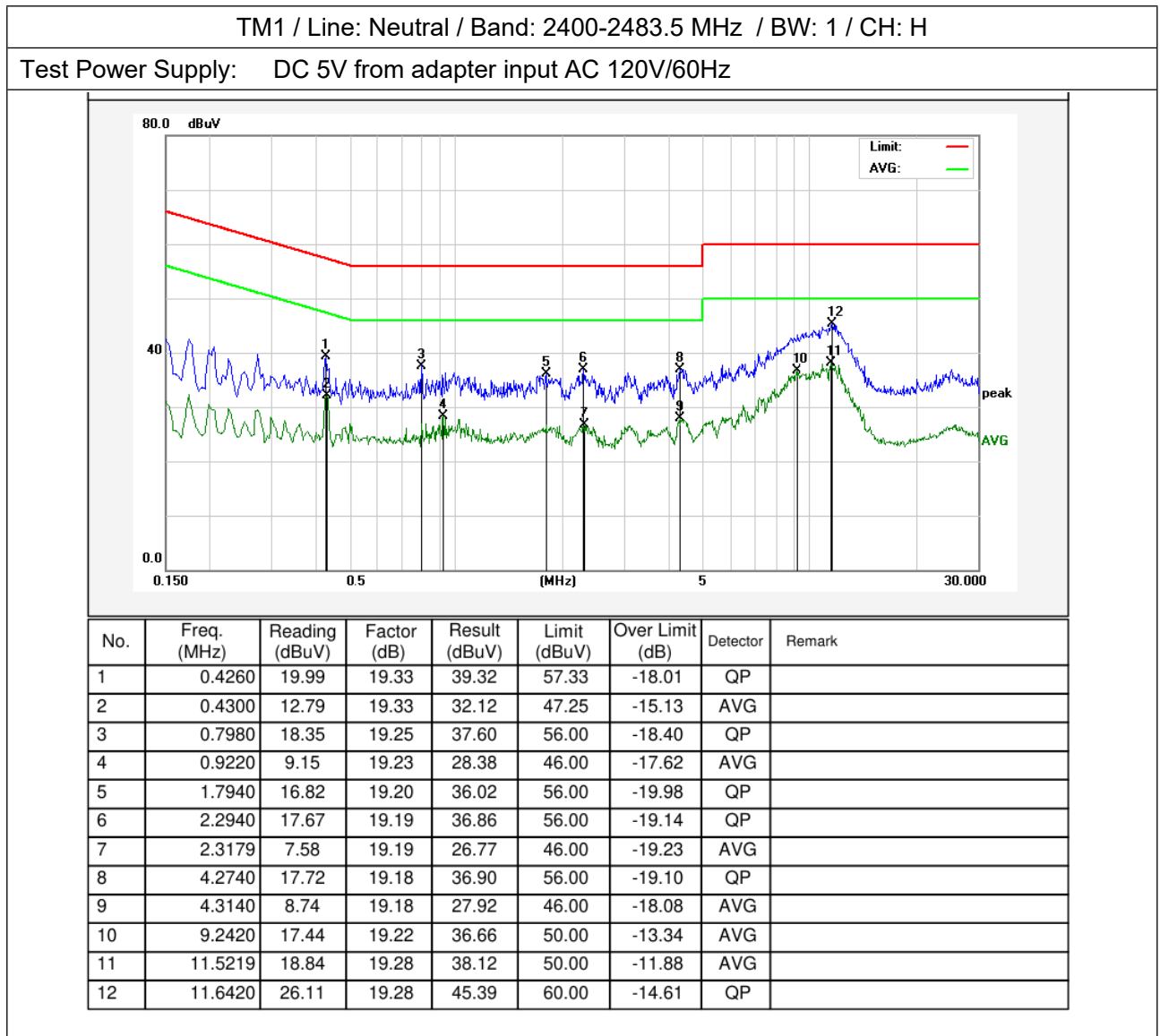


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Temperature:	24.5 °C	Humidity:	62 %	Atmospheric Pressure:	101 kPa
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Note:

1. Only record the worst data in the report.
2. Result(dBuV) = Reading(dBuV) + Factor(dB);
Over Limit(dB) = Result(dBuV) - Limit(dBuV)

4. 20dB Bandwidth

Test Requirement:	47 CFR 15.247(a)(1)
Test Limit:	Refer to 47 CFR 15.215(c), intentional radiators operating under the alternative provisions to the general emission limits, as contained in §§ 15.217 through 15.257 and in subpart E of this part, must be designed to ensure that the 20 dB bandwidth of the emission, or whatever bandwidth may otherwise be specified in the specific rule section under which the equipment operates, is contained within the frequency band designated in the rule section under which the equipment is operated.
Test Method:	ANSI C63.10-2020+Cor.1-2023, section 7.8.6, For occupied bandwidth measurements, use the procedure in 6.9.3. Frequency hopping shall be disabled for this test. KDB 558074 D01 15.247 Meas Guidance v05r02
Procedure:	The occupied bandwidth is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers are each equal to 0.5% of the total mean power of the given emission. The following procedure shall be used for measuring 99% power bandwidth: a) The instrument center frequency is set to the nominal EUT channel center frequency. The frequency span for the spectrum analyzer shall be between 1.5 times and 5.0 times the OBW. b) The nominal IF filter bandwidth (3 dB RBW) shall be in the range of 1% to 5% of the OBW, and VBW shall be at least three times the RBW, unless otherwise specified by the applicable requirement. c) Set the reference level of the instrument as required, keeping the signal from exceeding the maximum input mixer level for linear operation. In general, the peak of the spectral envelope shall be more than $[10 \log (OBW/RBW)]$ below the reference level. Specific guidance is given in 4.1.6.2. d) Step a) through step c) might require iteration to adjust within the specified range. e) Video averaging is not permitted. Where practical, a sample detection and single sweep mode shall be used. Otherwise, peak detection and max-hold mode (until the trace stabilizes) shall be used. f) Use the 99% power bandwidth function of the instrument (if available) and report the measured bandwidth. g) If the instrument does not have a 99% power bandwidth function, then the trace data points are recovered and directly summed in linear power terms. The recovered amplitude data points, beginning at the lowest frequency, are placed in a running sum until 0.5% of the total is reached; that frequency is recorded as the lower frequency. The process is repeated until 99.5% of the total is reached; that frequency is recorded as the upper frequency. The 99% power bandwidth is the difference between these two frequencies. h) The occupied bandwidth shall be reported by providing spectral plot(s) of the measuring instrument display; the plot axes and the scale units per division shall be clearly labeled. Tabular data may be reported in addition to the plot(s).

4.1. EUT Operation

Operating Environment:	
Test mode:	1: TX (Non-Hopping): Keep the EUT in continuously transmitting mode (non-

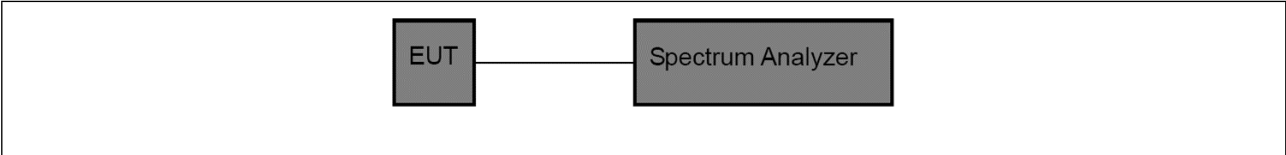
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	hopping).
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4.2. Test Setup



4.3. Test Data

Temperature:	25.2 °C	Humidity:	70 %	Atmospheric Pressure:	101 kPa
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Please Refer to Appendix for Details.

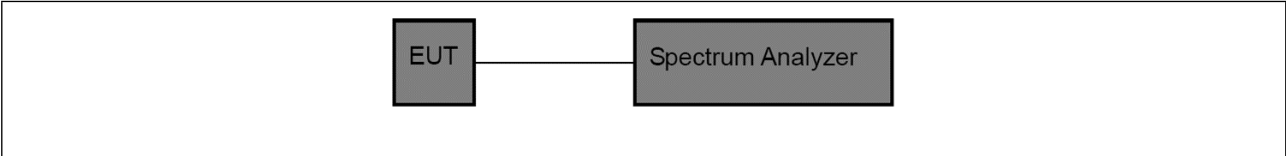
5. Maximum Conducted Output Power

Test Requirement:	47 CFR 15.247(b)(1)
Test Limit:	Refer to 47 CFR 15.247(b)(1), For frequency hopping systems operating in the 2400-2483.5 MHz band employing at least 75 non-overlapping hopping channels, and all frequency hopping systems in the 5725-5850 MHz band: 1 watt. For all other frequency hopping systems in the 2400-2483.5 MHz band: 0.125 watts.
Test Method:	ANSI C63.10-2020+Cor 1-2023, section 7.8.5 KDB 558074 D01 15.247 Meas Guidance v05r02

5.1. EUT Operation

Operating Environment:	
Test mode:	1: TX (Non-Hopping): Keep the EUT in continuously transmitting mode (non-hopping).

5.2. Test Setup



5.3. Test Data

Temperature:	25.2 °C	Humidity:	70 %	Atmospheric Pressure:	101 kPa
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Please Refer to Appendix for Details.

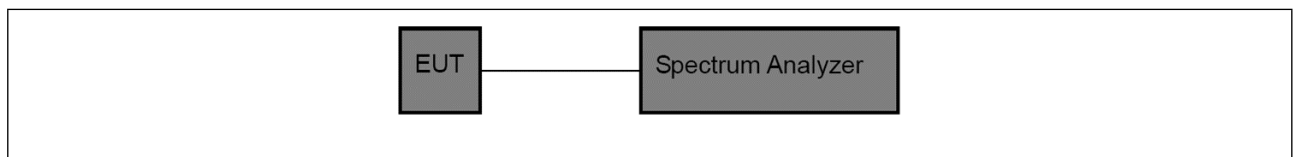
6. Channel Separation

Test Requirement:	47 CFR 15.247(a)(1)
Test Limit:	Refer to 47 CFR 15.247(a)(1), Frequency hopping systems shall have hopping channel carrier frequencies separated by a minimum of 25 kHz or the 20 dB bandwidth of the hopping channel, whichever is greater. Alternatively, frequency hopping systems operating in the 2400-2483.5 MHz band may have hopping channel carrier frequencies that are separated by 25 kHz or two-thirds of the 20 dB bandwidth of the hopping channel, whichever is greater, provided the systems operate with an output power no greater than 125 mW.
Test Method:	ANSI C63.10-2020+Cor 1-2023, section 7.8.2 KDB 558074 D01 15.247 Meas Guidance v05r02
Procedure:	The EUT shall have its hopping function enabled. Use the following spectrum analyzer settings: a) Span: Wide enough to capture the peaks of two adjacent channels. b) RBW: Start with the RBW set to approximately 30% of the channel spacing; adjust as necessary to best identify the center of each individual channel. c) Video (or average) bandwidth (VBW) $\geq$ RBW. d) Sweep: No faster than coupled (auto) time. e) Detector function: Peak. f) Trace: Max-hold. g) Allow the trace to stabilize. Use the marker-delta function to determine the separation between the peaks of the adjacent channels. Compliance of an EUT with the appropriate regulatory limit shall be determined. A spectral plot of the data shall be included in the test report.

6.1. EUT Operation

Operating Environment:	
Test mode:	2: TX (Hopping): Keep the EUT in continuously transmitting mode (hopping).

6.2. Test Setup



6.3. Test Data

Temperature:	25.2 °C	Humidity:	70 %	Atmospheric Pressure:	101 kPa
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Please Refer to Appendix for Details.

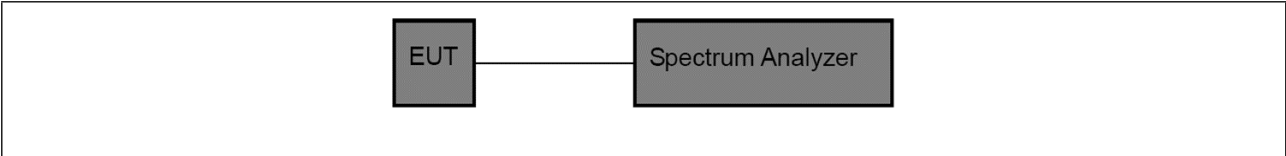
7. Number of Hopping Frequencies

Test Requirement:	47 CFR 15.247(a)(1)(iii)
Test Limit:	Refer to 47 CFR 15.247(a)(1)(iii), Fequency hopping systems in the 2400-2483.5 MHz band shall use at least 15 channels. The average time of occupancy on any channel shall not be greater than 0.4 seconds within a period of 0.4 seconds multiplied by the number of hopping channels employed. Frequency hopping systems may avoid or suppress transmissions on a particular hopping frequency provided that a minimum of 15 channels are used.
Test Method:	ANSI C63.10-2020+Cor 1-2023, section 7.8.3 KDB 558074 D01 15.247 Meas Guidance v05r02

7.1. EUT Operation

Operating Environment:	
Test mode:	2: TX (Hopping): Keep the EUT in continuously transmitting mode (hopping).

7.2. Test Setup



7.3. Test Data

Temperature:	25.2 °C	Humidity:	70 %	Atmospheric Pressure:	101 kPa
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Please Refer to Appendix for Details.

8. Dwell Time

Test Requirement:	47 CFR 15.247(a)(1)(iii)
Test Limit:	Refer to 47 CFR 15.247(a)(1)(iii), Frequency hopping systems in the 2400-2483.5 MHz band shall use at least 15 channels. The average time of occupancy on any channel shall not be greater than 0.4 seconds within a period of 0.4 seconds multiplied by the number of hopping channels employed. Frequency hopping systems may avoid or suppress transmissions on a particular hopping frequency provided that a minimum of 15 channels are used.
Test Method:	ANSI C63.10-2020+Cor 1-2023, section 7.8.4 KDB 558074 D01 15.247 Meas Guidance v05r02
Procedure:	The dwell time per hop on a channel is the time from the start of the first transmission to the end of the last transmission for that hop. If the device has a single transmission per hop then the dwell time is the duration of that transmission. If the device has a multiple transmissions per hop then the dwell time is measured from the start of the first transmission to the end of the last transmission. The time of occupancy is the total time that the device dwells on a channel over an observation period specified in the regulatory requirement. To determine the time of occupancy the spectrum analyzer will be configured to measure both the dwell time per hop and the number of times the device transmits on a specific channel in a given period. The EUT shall have its hopping function enabled. Compliance with the requirements shall be made with the minimum and with the maximum number of channels enabled. If the dwell time per channel does not vary with the number of channels then compliance with the requirements may be based on the minimum number of channels. If the device supports different dwell times per channel (example Bluetooth devices can dwell on a channel for 1, 3 or 5 time slots) then measurements can be limited to the longest dwell time with the minimum number of channels. Use the following spectrum analyzer settings to determine the dwell time per hop: a) Span: Zero span, centered on a hopping channel. b) RBW shall be $\leq$ channel spacing and where possible RBW should be set $\gg 1/T$, where T is the expected transmission time per hop. c) Sweep time: Set so that the start of the first transmission and end of the last transmission for the hop are clearly captured. Setting the sweep time to be slightly longer than the hopping period per channel (hopping period = $1/\text{hopping rate}$) should achieve this. d) Use a video trigger, where possible with a trigger delay, so that the start of the transmission is clearly observed. The trigger level might need adjustment to reduce the chance of triggering when the system hops on an adjacent channel. e) Detector function: Peak. f) Trace: Clear-write, single sweep. g) Place markers at the start of the first transmission on the channel and at the end of the last transmission. The dwell time per hop is the time between

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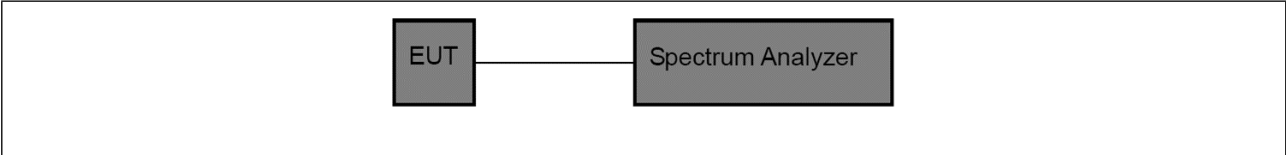
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	these two markers. To determine the number of hops on a channel in the regulatory observation period repeat the measurement using a longer sweep time. When the device uses a single hopping sequence the period of measurement should be sufficient to capture at least 2 hops. When the device uses a dynamic hopping sequence, or the sequence varies, the period of measurement may need to capture multiple hops to better determine the average time of occupancy. Count the number of hops on the channel across the sweep time. The average number of hops on the same channel within the regulatory observation period is calculated from the number of hops on the channel divided by the spectrum analyzer sweep time multiplied by the regulatory observation period. For example, if three hops are counted with an analyzer sweep time of 500 ms and the regulatory observation period is 10 s, then the number of hops in that ten seconds is $3 / 0.5 \times 10$, or 60 hops. The average time of occupancy is calculated by multiplying the dwell time per hop by the number of hops in the observation period.
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8.1. EUT Operation

Operating Environment:	
Test mode:	2: TX (Hopping): Keep the EUT in continuously transmitting mode (hopping).

8.2. Test Setup



8.3. Test Data

Temperature:	25.2 °C	Humidity:	70 %	Atmospheric Pressure:	101 kPa
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Please Refer to Appendix for Details.

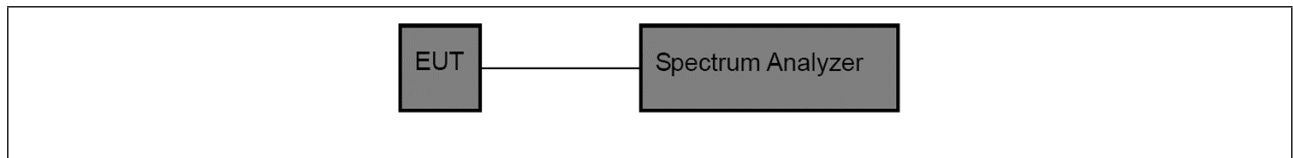
9. Emissions in non-restricted frequency bands

Test Requirement:	47 CFR 15.247(d)
Test Limit:	Refer to 47 CFR 15.247(d), In any 100 kHz bandwidth outside the frequency band in which the spread spectrum or digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at least 20 dB below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power, based on either an RF conducted or a radiated measurement, provided the transmitter demonstrates compliance with the peak conducted power limits. If the transmitter complies with the conducted power limits based on the use of RMS averaging over a time interval, as permitted under paragraph (b)(3) of this section, the attenuation required under this paragraph shall be 30 dB instead of 20 dB. Attenuation below the general limits specified in § 15.209(a) is not required.
Test Method:	ANSI C63.10-2020+Cor 1-2023 section 7.8.7 KDB 558074 D01 15.247 Meas Guidance v05r02

9.1. EUT Operation

Operating Environment:	
Test mode:	1: TX (Non-Hopping): Keep the EUT in continuously transmitting mode (non-hopping). 2: TX (Hopping): Keep the EUT in continuously transmitting mode (hopping).

9.2. Test Setup



9.3. Test Data

Temperature:	25.2 °C	Humidity:	70 %	Atmospheric Pressure:	101 kPa
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Please Refer to Appendix for Details.

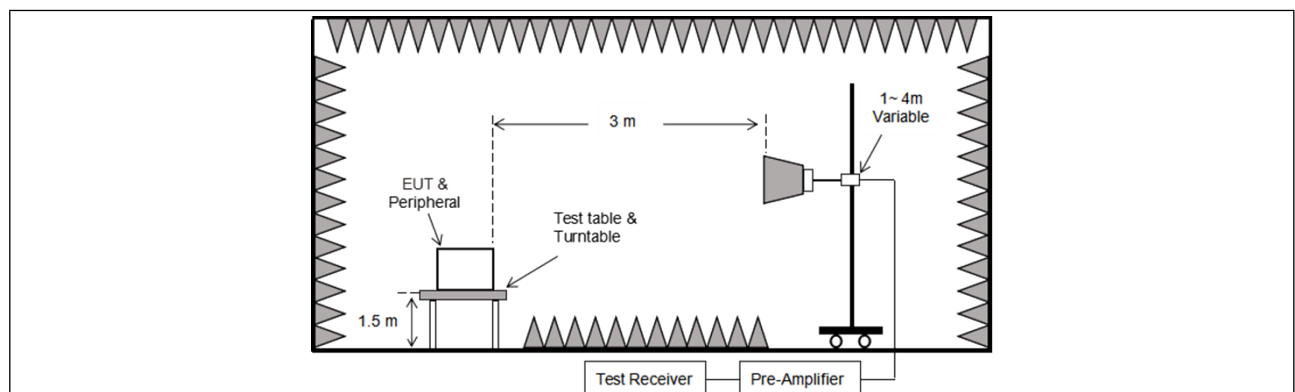
10. Band edge emissions (Radiated)

Test Requirement:	Refer to 47 CFR 15.247(d), In addition, radiated emissions which fall in the restricted bands, as defined in § 15.205(a), must also comply with the radiated emission limits specified in § 15.209(a)(see § 15.205(c)).		
Test Limit:	Frequency (MHz)	Field strength (microvolts/meter)	Measurement distance (meters)
	0.009-0.490	2400/F(kHz)	300
	0.490-1.705	24000/F(kHz)	30
	1.705-30.0	30	30
	30-88	100 **	3
	88-216	150 **	3
	216-960	200 **	3
	Above 960	500	3
	** Except as provided in paragraph (g), fundamental emissions from intentional radiators operating under this section shall not be located in the frequency bands 54-72 MHz, 76-88 MHz, 174-216 MHz or 470-806 MHz. However, operation within these frequency bands is permitted under other sections of this part, e.g., §§ 15.231 and 15.241. In the emission table above, the tighter limit applies at the band edges. The emission limits shown in the above table are based on measurements employing a CISPR quasi-peak detector except for the frequency bands 9–90 kHz, 110–490 kHz and above 1000 MHz. Radiated emission limits in these three bands are based on measurements employing an average detector.		
Test Method:	ANSI C63.10-2020+Cor 1-2023 section 6.10 KDB 558074 D01 15.247 Meas Guidance v05r02		
Procedure:	ANSI C63.10-2020+Cor 1-2023 section 6.10.5.2		

10.1. EUT Operation

Operating Environment:	
Test mode:	1: TX (Non-Hopping): Keep the EUT in continuously transmitting mode (non-hopping).

10.2. Test Setup



10.3. Test Data

Temperature:	25.2 °C	Humidity:	70 %	Atmospheric Pressure:	101 kPa
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TM1 / CH: L						
Peak value:						
Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Result (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	polarization
2390.000	31.97	9.73	41.70	74.00	-32.30	Vertical
2325.948	33.43	9.73	43.16	74.00	-30.84	Vertical
2390.000	31.40	9.73	41.13	74.00	-32.87	Horizontal
2331.690	34.86	9.73	44.59	74.00	-29.41	Horizontal
TM1 / CH: H						
Peak value:						
Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Result (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	polarization
2483.500	27.66	9.91	37.57	74.00	-36.43	Vertical
2508.870	37.20	9.91	47.11	74.00	-26.89	Vertical
2483.500	29.76	9.91	39.67	74.00	-34.33	Horizontal
2508.253	30.64	9.91	40.55	74.00	-33.45	Horizontal
Note: Result=Reading+Factor, Over Limit=Result-Limit						

Remark: When the PK measure result value is less than the AVG limit value, the AV measure result values test not applicable.

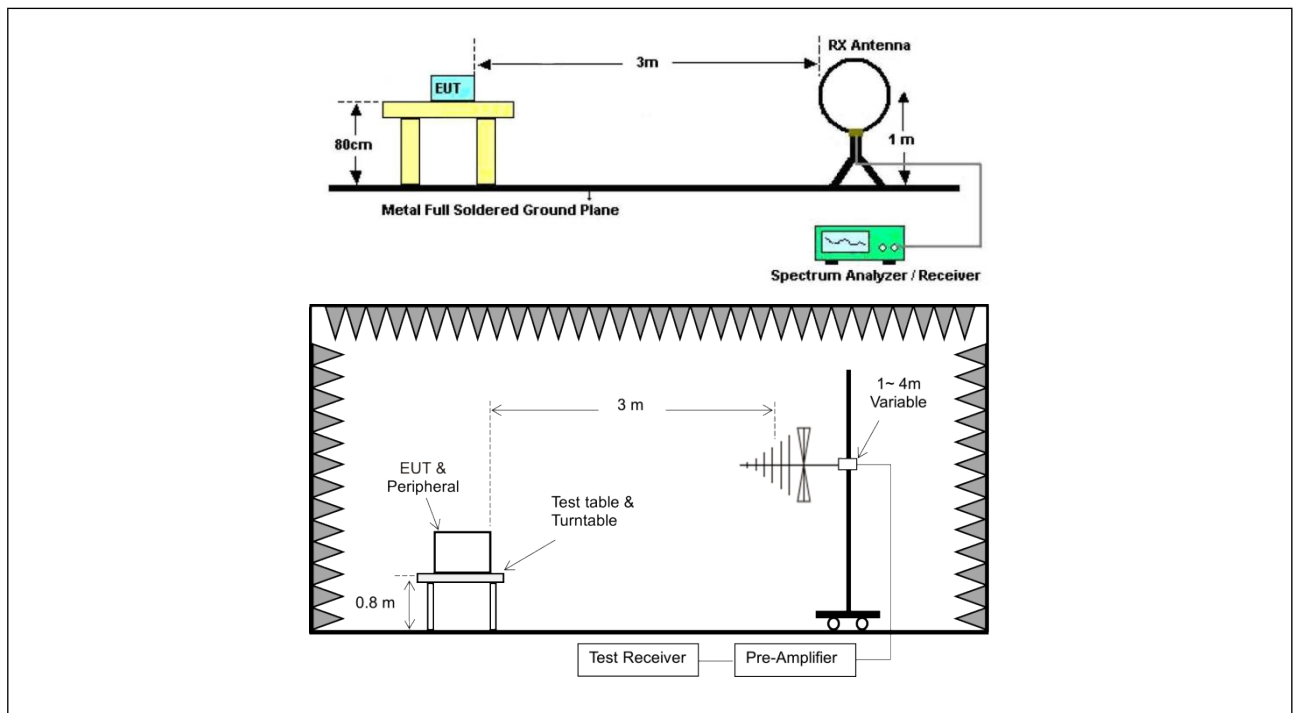
11. Emissions in restricted frequency bands (below 1GHz)

Test Requirement:	Refer to 47 CFR 15.247(d), In addition, radiated emissions which fall in the restricted bands, as defined in § 15.205(a), must also comply with the radiated emission limits specified in § 15.209(a)(see § 15.205(c)).		
Test Limit:	Frequency (MHz)	Field strength (microvolts/meter)	Measurement distance (meters)
	0.009-0.490	2400/F(kHz)	300
	0.490-1.705	24000/F(kHz)	30
	1.705-30.0	30	30
	30-88	100 **	3
	88-216	150 **	3
	216-960	200 **	3
	Above 960	500	3
	** Except as provided in paragraph (g), fundamental emissions from intentional radiators operating under this section shall not be located in the frequency bands 54-72 MHz, 76-88 MHz, 174-216 MHz or 470-806 MHz. However, operation within these frequency bands is permitted under other sections of this part, e.g., §§ 15.231 and 15.241. In the emission table above, the tighter limit applies at the band edges. The emission limits shown in the above table are based on measurements employing a CISPR quasi-peak detector except for the frequency bands 9–90 kHz, 110–490 kHz and above 1000 MHz. Radiated emission limits in these three bands are based on measurements employing an average detector.		
Test Method:	ANSI C63.10-2020+Cor 1-2023 section 6.5.4 KDB 558074 D01 15.247 Meas Guidance v05r02		
Procedure:	ANSI C63.10-2020+Cor 1-2023 section 6.5.4		

11.1. EUT Operation

Operating Environment:	
Test mode:	1: TX (Non-Hopping): Keep the EUT in continuously transmitting mode (non-hopping).

11.2. Test Setup



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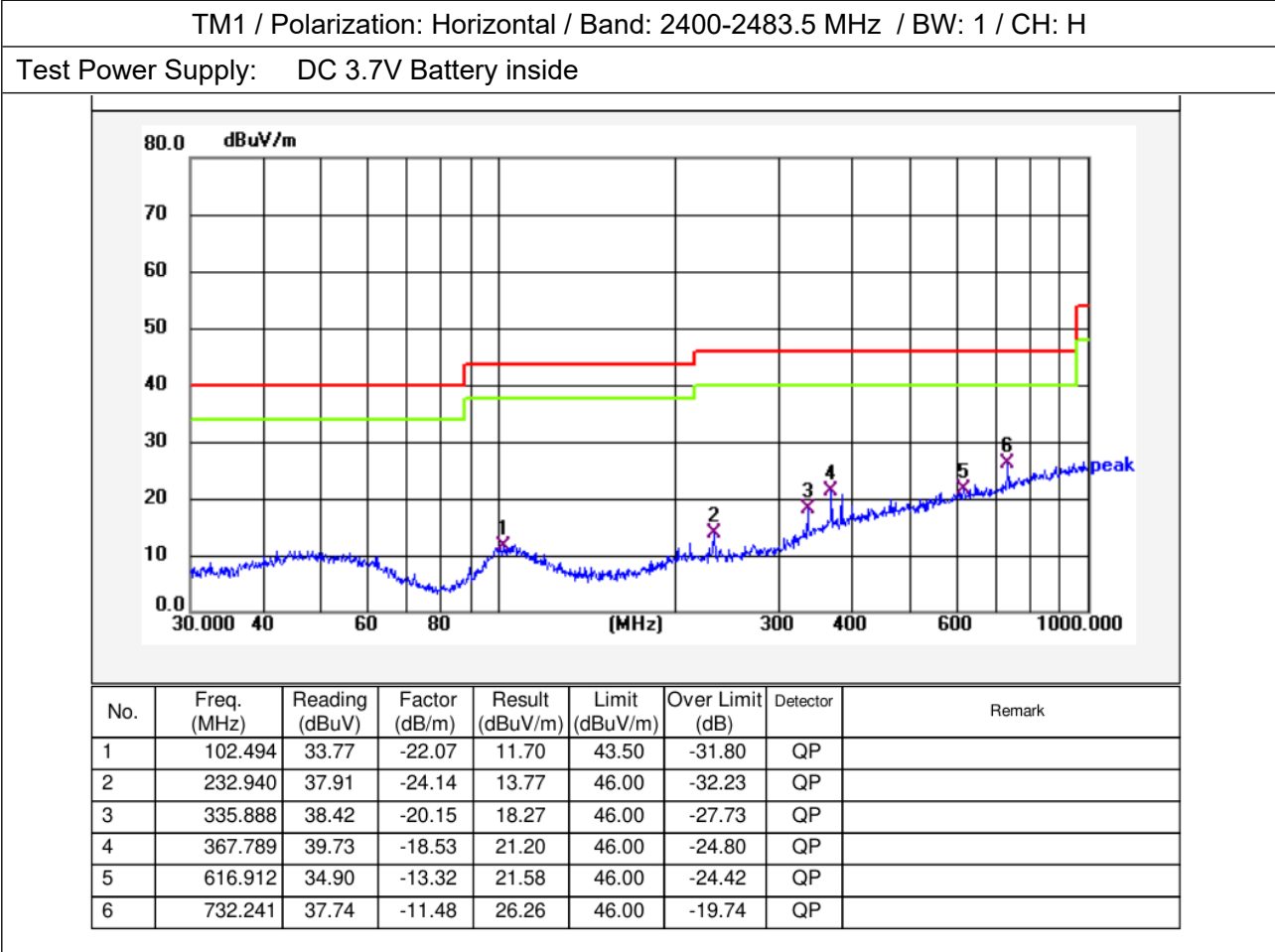
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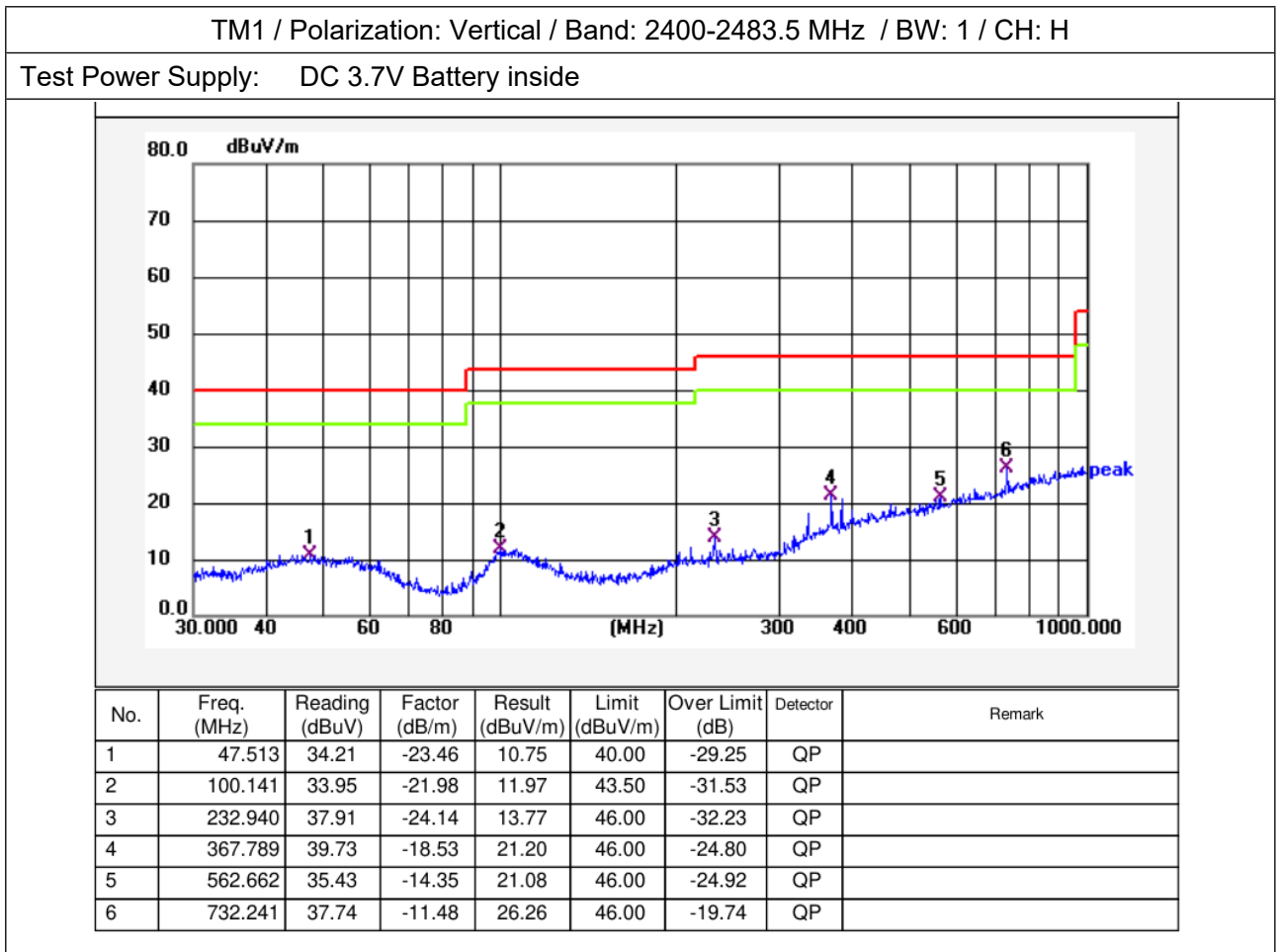
11.3. Test Data

The test results of 9kHz-30MHz was attenuated more than 20dB below the permissible limits, so the results don't record in the report.

Temperature:	23.7 °C	Humidity:	55 %	Atmospheric Pressure:	101 kPa
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Temperature:	23.7 °C	Humidity:	55 %	Atmospheric Pressure:	101 kPa
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Note:

1. Only record the worst data in the report.
2. $\text{Result(dBuV/m)} = \text{Reading(dBuV)} + \text{Factor(dB/m)}$;
 $\text{Over Limit(dB)} = \text{Result(dBuV/m)} - \text{Limit(dBuV/m)}$

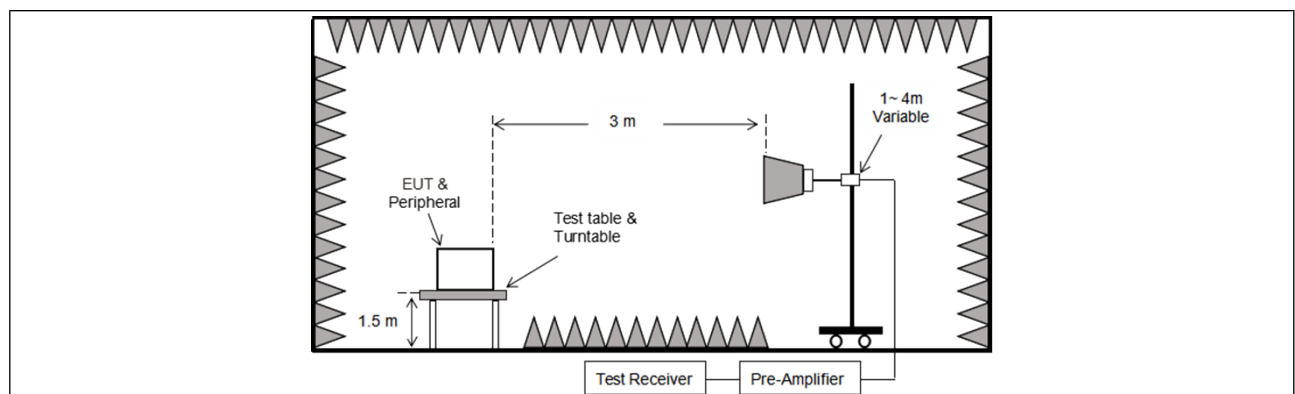
12. Emissions in restricted frequency bands (above 1GHz)

Test Requirement:	Refer to 47 CFR 15.247(d), in addition, radiated emissions which fall in the restricted bands, as defined in § 15.205(a), must also comply with the radiated emission limits specified in § 15.209(a)(see § 15.205(c)).		
Test Limit:	Frequency (MHz)	Field strength (microvolts/meter)	Measurement distance (meters)
	0.009-0.490	2400/F(kHz)	300
	0.490-1.705	24000/F(kHz)	30
	1.705-30.0	30	30
	30-88	100 **	3
	88-216	150 **	3
	216-960	200 **	3
	Above 960	500	3
** Except as provided in paragraph (g), fundamental emissions from intentional radiators operating under this section shall not be located in the frequency bands 54-72 MHz, 76-88 MHz, 174-216 MHz or 470-806 MHz. However, operation within these frequency bands is permitted under other sections of this part, e.g., §§ 15.231 and 15.241. In the emission table above, the tighter limit applies at the band edges. The emission limits shown in the above table are based on measurements employing a CISPR quasi-peak detector except for the frequency bands 9–90 kHz, 110–490 kHz and above 1000 MHz. Radiated emission limits in these three bands are based on measurements employing an average detector.			
Test Method:	ANSI C63.10-2020+Cor 1-2023 section 6.5.4 KDB 558074 D01 15.247 Meas Guidance v05r02		
Procedure:	ANSI C63.10-2020+Cor 1-2023 section 6.5.4		

12.1. EUT Operation

Operating Environment:	
Test mode:	1: TX (Non-Hopping): Keep the EUT in continuously transmitting mode (non-hopping).

12.2. Test Setup



12.3. Test Data

Temperature:	25.2 °C	Humidity:	70 %	Atmospheric Pressure:	101 kPa
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TM1 / CH: L						
Peak value:						
Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Result (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	polarization
4806.00	32.65	15.27	47.92	74.00	-26.08	Vertical
7209.00	33.63	18.09	51.72	74.00	-22.28	Vertical
9612.00	35.69	23.76	59.45	74.00	-14.55	Vertical
12015.00	*			74.00		Vertical
14418.00	*			74.00		Vertical
4806.00	32.93	15.27	48.20	74.00	-25.80	Horizontal
7209.00	33.42	18.09	51.51	74.00	-22.49	Horizontal
9612.00	31.16	23.76	54.92	74.00	-19.08	Horizontal
12015.00	*			74.00		Horizontal
14418.00	*			74.00		Horizontal
Average value:						
Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Result (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	polarization
4806.00	22.03	15.27	37.30	54.00	-16.70	Vertical
7209.00	22.66	18.09	40.75	54.00	-13.25	Vertical
9612.00	24.71	23.76	48.47	54.00	-5.53	Vertical
12015.00	*			54.00		Vertical
14418.00	*			54.00		Vertical
4806.00	21.28	15.27	36.55	54.00	-17.45	Horizontal
7209.00	22.48	18.09	40.57	54.00	-13.43	Horizontal
9612.00	20.47	23.76	44.23	54.00	-9.77	Horizontal
12015.00	*			54.00		Horizontal
14418.00	*			54.00		Horizontal

TM1 / CH: M						
Peak value:						
Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Result (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	polarization
4882.00	32.67	15.42	48.09	74.00	-25.91	Vertical
7323.00	33.48	18.02	51.50	74.00	-22.50	Vertical
9764.00	34.70	23.80	58.50	74.00	-15.50	Vertical
12205.00	*			74.00		Vertical
14646.00	*			74.00		Vertical
4882.00	32.63	15.42	48.05	74.00	-25.95	Horizontal
7323.00	33.41	18.02	51.43	74.00	-22.57	Horizontal
9764.00	30.86	23.80	54.66	74.00	-19.34	Horizontal
12205.00	*			74.00		Horizontal
14646.00	*			74.00		Horizontal
Average value:						
Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Result (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	polarization
4882.00	21.76	15.42	37.18	54.00	-16.82	Vertical
7323.00	22.76	18.02	40.78	54.00	-13.22	Vertical
9764.00	24.57	23.80	48.37	54.00	-5.63	Vertical
12205.00	*			54.00		Vertical
14646.00	*			54.00		Vertical
4882.00	21.19	15.42	36.61	54.00	-17.39	Horizontal
7323.00	22.04	18.02	40.06	54.00	-13.94	Horizontal
9764.00	20.98	23.80	44.78	54.00	-9.22	Horizontal
12205.00	*			54.00		Horizontal
14646.00	*			54.00		Horizontal

TM1 / CH: H						
Peak value:						
Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Result (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	polarization
4960.00	32.94	15.58	48.52	74.00	-25.48	Vertical
7440.00	33.49	17.93	51.42	74.00	-22.58	Vertical
9920.00	35.25	23.83	59.08	74.00	-14.92	Vertical
12400.00	*			74.00		Vertical
14880.00	*			74.00		Vertical
4960.00	32.70	15.58	48.28	74.00	-25.72	Horizontal
7440.00	33.44	17.93	51.37	74.00	-22.63	Horizontal
9920.00	31.54	23.83	55.37	74.00	-18.63	Horizontal
12400.00	*			74.00		Horizontal
14880.00	*			74.00		Horizontal
Average value:						
Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Result (dBuV/m)	Limit (dBuV/m)	Over Limit (dB)	polarization
4960.00	22.88	15.58	38.46	54.00	-15.54	Vertical
7440.00	23.77	17.93	41.70	54.00	-12.30	Vertical
9920.00	25.12	23.83	48.95	54.00	-5.05	Vertical
12400.00	*			54.00		Vertical
14880.00	*			54.00		Vertical
4960.00	22.63	15.58	38.21	54.00	-15.79	Horizontal
7440.00	23.41	17.93	41.34	54.00	-12.66	Horizontal
9920.00	20.88	23.83	44.71	54.00	-9.29	Horizontal
12400.00	*			54.00		Horizontal
14880.00	*			54.00		Horizontal

Remark:

1. Result =Reading + Factor
2. Test frequency are from 1GHz to 25GHz, “*” means the test results were attenuated more than 20dB below the permissible limits, so the results don't record in the report.

APPENDIX I -- TEST SETUP PHOTOGRAPH

Please refer to separated files Appendix I -- Test Setup Photograph_RF

APPENDIX II -- EXTERNAL PHOTOGRAPH

Please refer to separated files Appendix II -- External Photograph

APPENDIX III -- INTERNAL PHOTOGRAPH

Please refer to separated files Appendix III -- Internal Photograph

----- End of Report -----